CRMGGH1003D

N-Channel 100V, 2.5mΩ Typ. Power MOSFET

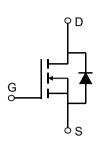
Description

Features

• 100V, 165A

 $R_{DS(ON)}$ Typ = 2.5m Ω @ V_{GS} = 10V

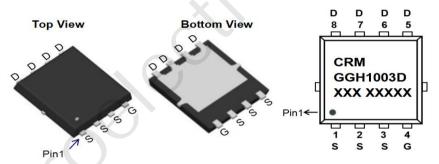
- Advanced Split Gate Trench Technology
- Excellent R_{DS(ON)} and Low Gate Charge
- 100% UIS TESTED!
- 100% ΔVds TESTED!





Application

- Load Switch
- PWM Application
- Power Management



Marking and Pin Assignment

Package Marking and Ordering Information

Device	Marking	Package	Outline	Reel Size	Reel (pcs)	Per Carton (pcs)
CRMGGH1003D	CRMGGH1003D	PDFN5x6-8L	TAPING	13"	5000	60000

Absolute Maximum Ratings (@ T_J = 25°C unless otherwise specified)

Symbol	Parameter		Value	Units
V_{DS}	Drain-to-Source Voltage		100	V
V _{GS}	Gate-to-Source Voltage		±20	V
_	Continuous Drain Current	T _C = 25°C	165	А
I _D		T _C = 100°C	99	А
I _{DM}	Pulsed Drain Current ⁽¹⁾		660	Α
E _{AS}	Single Pulsed Avalanche Energy (2)		473	mJ
P_{D}	Power Dissipation $T_C = 25^{\circ}C$		171	W
$R_{ heta JC}$	Thermal Resistance, Junction to Case		0.73	°C/W
T_{J}, T_{STG}	Junction & Storage Temperature Range		-55 to 150	°C

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Electrical Characteristics (T_J = 25°C unless otherwise specified)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Off Char	acteristics					
V _{(BR)DSS}	Drain-Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	100	-	-	V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 100V, V _{GS} = 0V	-	-	1.0	μА
I _{GSS}	Gate-Body Leakage Current	$V_{DS} = 0V, V_{GS} = \pm 20V$	-	-	±100	nA
On Chara	acteristics				6	
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.4	2.8	3.6	V
R _{DS(ON)}	Static Drain-Source ON-Resistance ⁽³⁾	V _{GS} = 10V, I _D = 30A	-	2.5	3.2	mΩ
Dynamic	Characteristics					
C _{iss}	Input Capacitance		- /	3832	-	pF
C_{oss}	Output Capacitance	$V_{GS} = 0V, V_{DS} = 50V,$ f = 1MHz	-	1546	-	pF
C_{rss}	Reverse Transfer Capacitance	1 - 1101112	X - \	20	-	pF
Q_g	Total Gate Charge		-	68	-	nC
Q_{gs}	Gate Source Charge	$V_{GS} = 0 \text{ to } 10V$ $V_{DS} = 50V, I_{D} = 20A$) .	16.5	-	nC
Q_{gd}	Gate Drain("Miller") Charge	V _{DS} - 30 V, I _D - 20A	-	15	-	nC
Switchin	g Characteristics					
t _{d(on)}	Turn-On DelayTime		-	18.5	-	ns
t_r	Turn-On Rise Time	$V_{GS} = 10V, V_{DD} = 50V$	-	16	-	ns
$t_{\text{d(off)}}$	Turn-Off DelayTime	$I_D = 40A$, $R_{GEN} = 3\Omega$	-	18	-	ns
t_f	Turn-Off Fall Time		-	15.5	-	ns
Drain-So	urce Diode Characteristics and M	Max Ratings				
Is	Maximum Continuous Drain to Source Diode Forward Current			-	165	Α
I _{SM}	Maximum Pulsed Drain to Source Diode Forward Current		-	-	660	Α
V_{SD}	Drain to Source Diode Forward Voltage	$V_{GS} = 0V, I_{S} = 30A$	-	-	1.2	V
trr	Body Diode Reverse Recovery Time	1 404 1777 40047	-	78	-	ns
Qrr	Body Diode Reverse Recovery Charge	$I_F = 40A$, di/dt = 100A/us	_	170	_	nC

Notes:

^{1.} Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature.

^{2.} E_{AS} condition: Starting T_J =25°C, V_{DD} =50V, V_G =10V, R_G =25ohm, L=0.5mH, I_{AS} =43.5A

^{3.} Pulse Test: Pulse Width $\!\!\!\!<\!300\mu s,$ Duty Cycle $\!\!\!<\!0.5\%.$

Typical Performance Characteristics

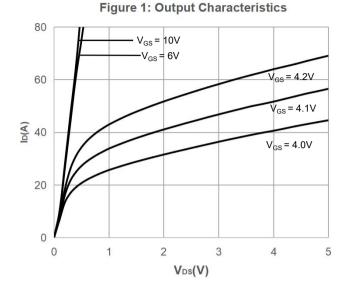


Figure 3: On-resistance vs. Drain Current

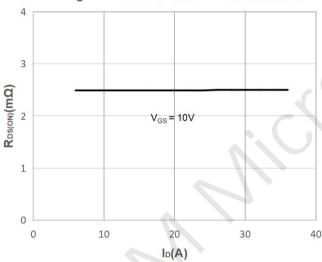


Figure 5: Gate Charge Characteristics

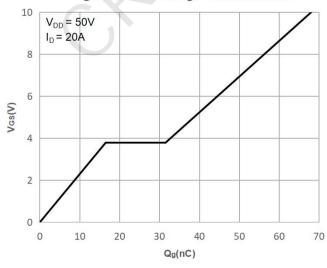


Figure 2: Typical Transfer Characteristics

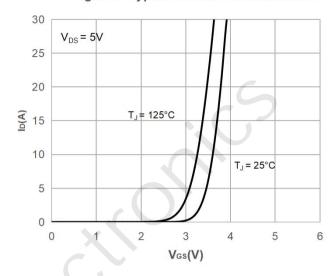


Figure 4: Body Diode Characteristics

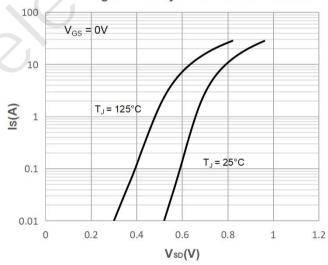
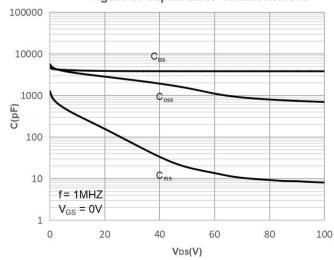


Figure 6: Capacitance Characteristics



Typical Performance Characteristics

Figure 7: Normalized Breakdown voltage vs.
Junction Temperature

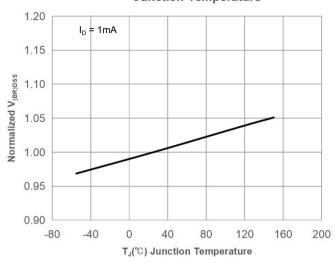


Figure 9: Maximum Safe Operating Area

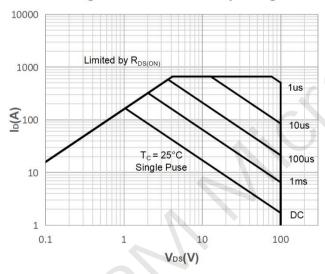


Figure 11: Normalized Maximum Transient

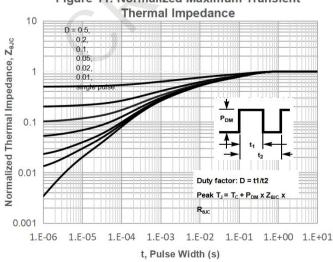


Figure 8: Normalized on Resistance vs. Junction Temperature

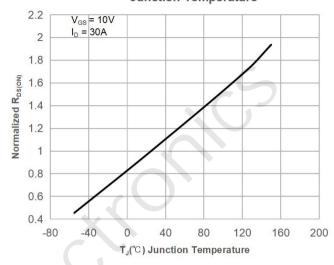


Figure 10: Maximum Continuous Drian
Current vs. Case Temperature

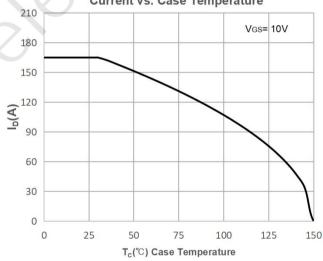
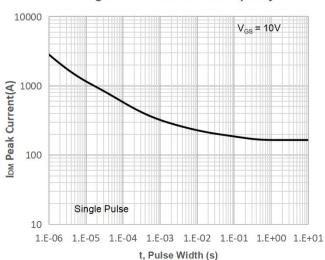


Figure 12: Peak Current Capacity





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Test Circuit

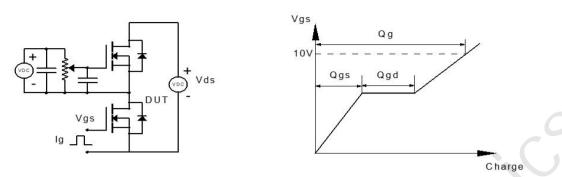


Figure 1: Gate Charge Test Circuit & Waveform

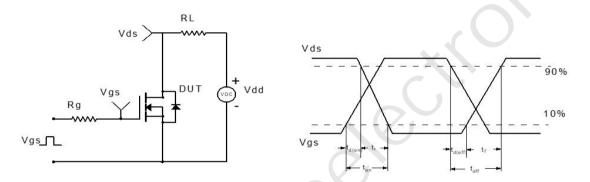


Figure 2: Resistive Switching Test Circuit & Waveform

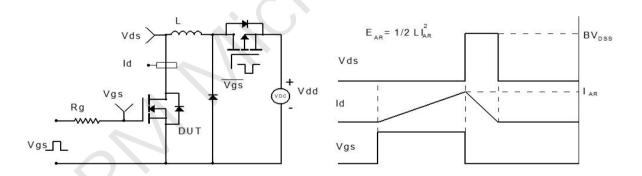


Figure 3: Unclamped Inductive Switching Test Circuit& Waveform

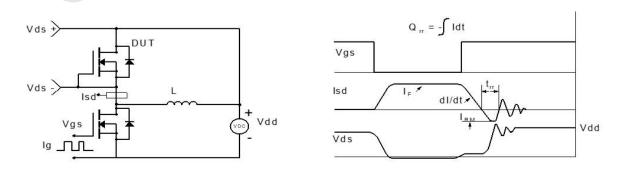
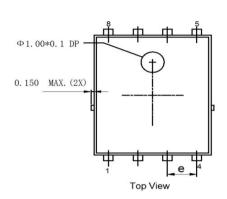
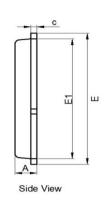
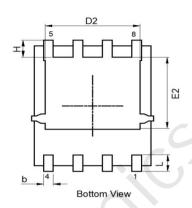


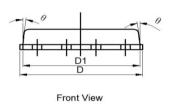
Figure 4: Diode Recovery Test Circuit & Waveform

Package Mechanical Data(PDFN5x6-8L)









DIM.	MILLIMETER				
DIM.	MIN.	NOM.	MAX.		
Α	0.90	1.00	1.10		
b	0.31	0.41	0.51		
С	0.21	0.25	0.34		
D	5.05	5.20	5.40		
D1	4.95	5.05	5.15		
D2	4.00	4.10	4.20		
E	6.30	6.40	6.50		
E1	5.75	5.85	5.95		
E2	3.43	3.53	3.63		
е	1.27BSC				
Н	0.73	0.83	0.93		
L	0.61	0.71	0.81		
θ	0°		12°		

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